

- ★ Green Device Available
- ★ Super Low Gate Charge
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology

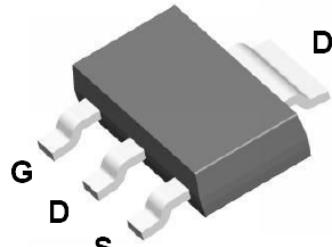
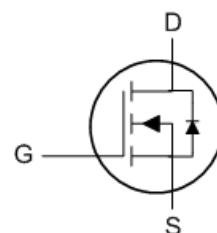
**Product Summary**

BVDSS	RDS(ON)	ID
60V	62 mΩ	5A

**Description**

The XR6005K is the high cell density trenched N-ch MOSFETs, which provides excellent RDS(ON) and efficiency for most of the small power switching and load switch applications.

The XR6005K meet the RoHS and Green Product requirement with full function reliability approved.

**SOT223 Pin Configuration****SOT-223-3L****Absolute Maximum Ratings ( $T_A=25^\circ\text{C}$  unless otherwise noted)**

Parameter		Symbol	Limit	Unit
Drain-source Voltage		$V_{DS}$	60	V
Gate-source Voltage		$V_{GS}$	$\pm 20$	V
Drain Current	$T_A=25^\circ\text{C}$	$I_D$	5	A
	$T_A=100^\circ\text{C}$		3	
Pulsed Drain Current <sup>A</sup>		$I_{DM}$	20	A
Total Power Dissipation <sup>B</sup>	$T_A=25^\circ\text{C}$	$P_D$	1.2	W
	$T_A=100^\circ\text{C}$		0.45	
Junction and Storage Temperature Range		$T_J, T_{STG}$	-55~+150	°C

**Thermal resistance**

Parameter		Symbol	Typ	Max	Units
Thermal Resistance Junction-to-Ambient <sup>C</sup>	Steady-State	$R_{\theta JA}$	85	105	°C/W

## N-Ch 60V Fast Switching MOSFETs

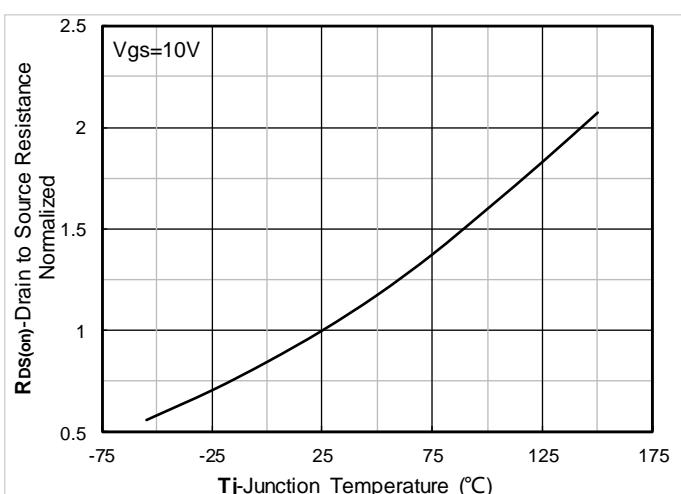
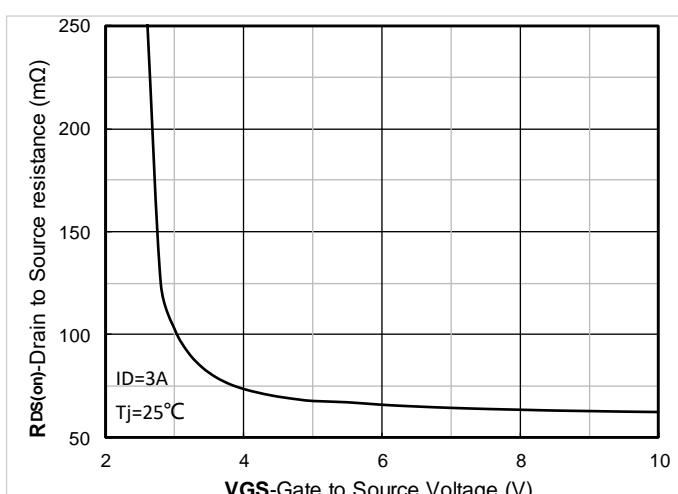
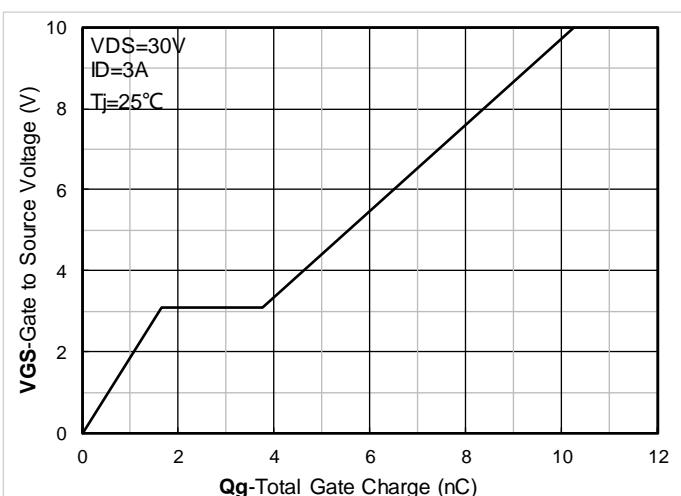
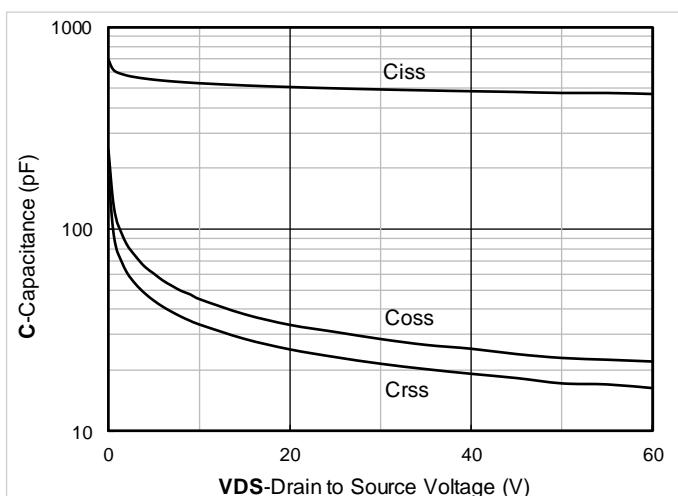
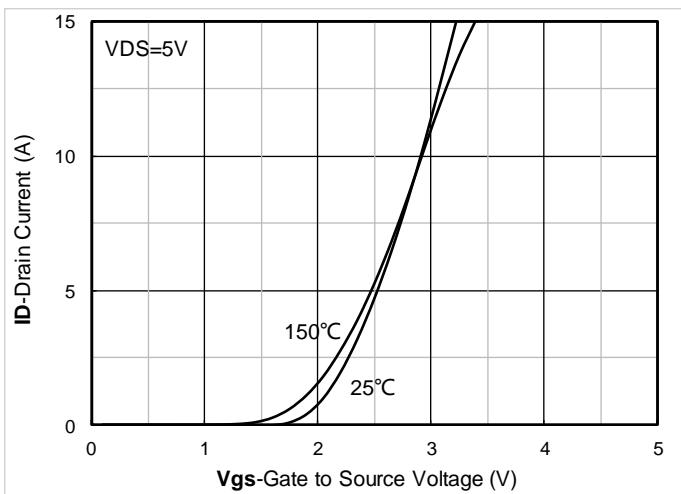
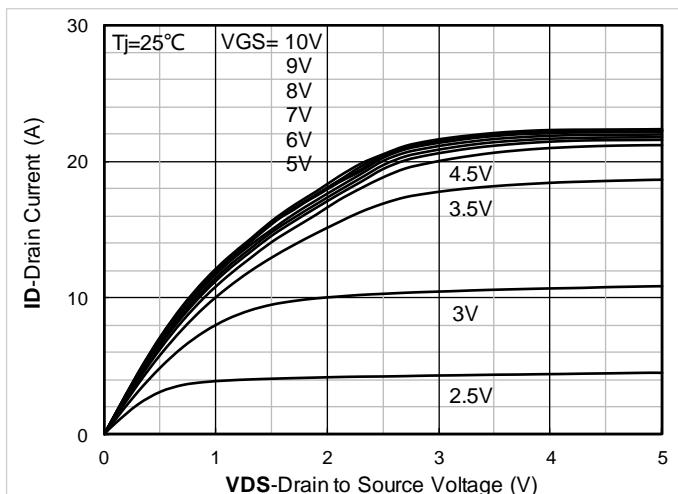
■ Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Static Parameter</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	60	-	-	V
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}}=60\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	$\mu\text{A}$
		$V_{\text{DS}}=60\text{V}, V_{\text{GS}}=0\text{V}, T_J=150^\circ\text{C}$	-	-	100	
Gate-Body Leakage Current	$I_{\text{GSS}}$	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	0.9	1.35	2	V
Static Drain-Source On-Resistance	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=3\text{A}$	-	62	85	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}, I_{\text{D}}=3\text{A}$	-	69	95	
Diode Forward Voltage	$V_{\text{SD}}$	$I_{\text{S}}=3\text{A}, V_{\text{GS}}=0\text{V}$	-	0.85	1.2	V
Gate resistance	$R_{\text{G}}$	f=1MHz, Open drain	-	2	-	$\Omega$
Maximum Body-Diode Continuous Current	$I_{\text{S}}$		-	-	5	A
<b>Dynamic Parameters</b>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{DS}}=30\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	-	500	-	$\text{pF}$
Output Capacitance	$C_{\text{oss}}$		-	28	-	
Reverse Transfer Capacitance	$C_{\text{rss}}$		-	22	-	
<b>Switching Parameters</b>						
Total Gate Charge	$Q_{\text{g}}$	$V_{\text{GS}}=10\text{V}, V_{\text{DS}}=30\text{V}, I_{\text{D}}=3\text{A}$	-	10	-	$\text{nC}$
Gate-Source Charge	$Q_{\text{gs}}$		-	1.7	-	
Gate-Drain Charge	$Q_{\text{gd}}$		-	2.1	-	
Reverse Recovery Charge	$Q_{\text{rr}}$	$I_{\text{F}}=3\text{A}, \text{di}/\text{dt}=100\text{A/us}$	-	7	-	$\text{nC}$
Reverse Recovery Time	$t_{\text{rr}}$		-	33	-	ns
Turn-on Delay Time	$t_{\text{D(on)}}$	$V_{\text{GS}}=10\text{V}, V_{\text{DD}}=30\text{V}, R_{\text{L}}=20\Omega, R_{\text{GEN}}=3\Omega$	-	3.6	-	ns
Turn-on Rise Time	$t_{\text{r}}$		-	17.6	-	
Turn-off Delay Time	$t_{\text{D(off)}}$		-	13	-	
Turn-off fall Time	$t_{\text{f}}$		-	23	-	

A. Repetitive rating; pulse width limited by max. junction temperature.

B.  $P_d$  is based on max. junction temperature, using junction-case thermal resistance.C. The value of  $R_{\theta JA}$  is measured with the device mounted on the minimum recommend pad size, in the still air environment with  $T_A = 25^\circ\text{C}$ .The maximum allowed junction temperature of  $150^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

### ■ Typical Electrical and Thermal Characteristics Diagrams



## N-Ch 60V Fast Switching MOSFETs

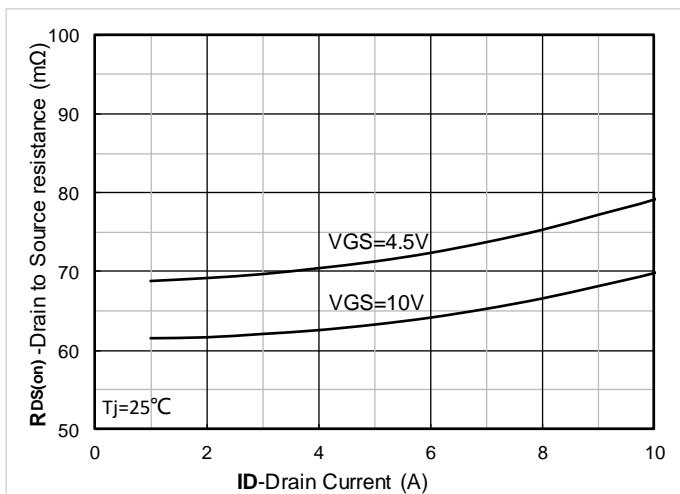
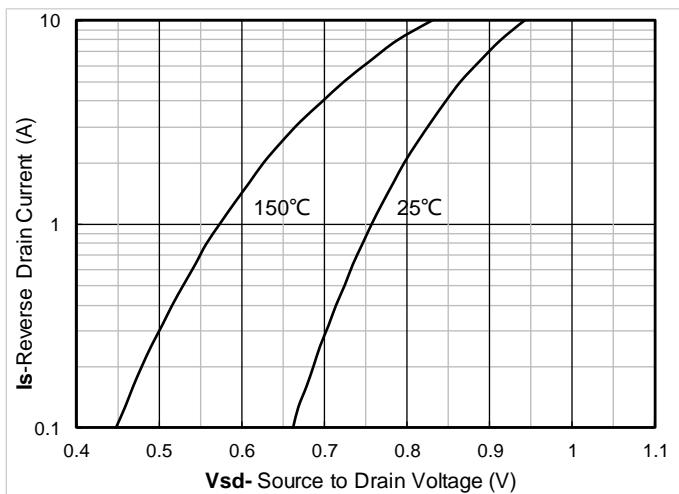
Figure 7.  $R_{DS(on)}$  VS Drain Current

Figure 8. Forward characteristics of reverse diode

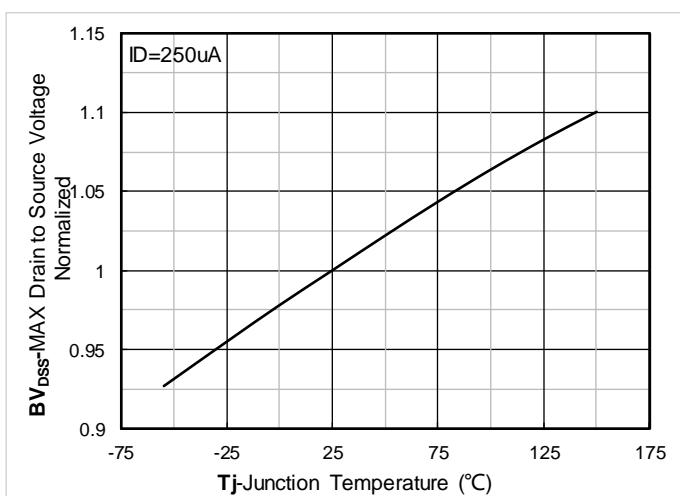


Figure 9. Normalized breakdown voltage

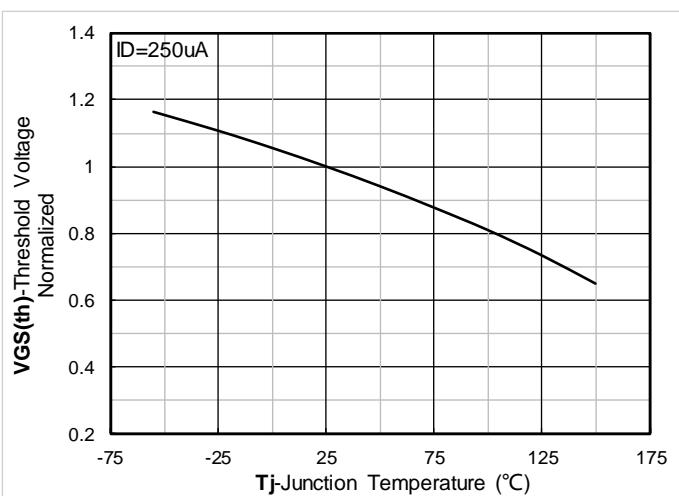


Figure 10. Normalized Threshold voltage

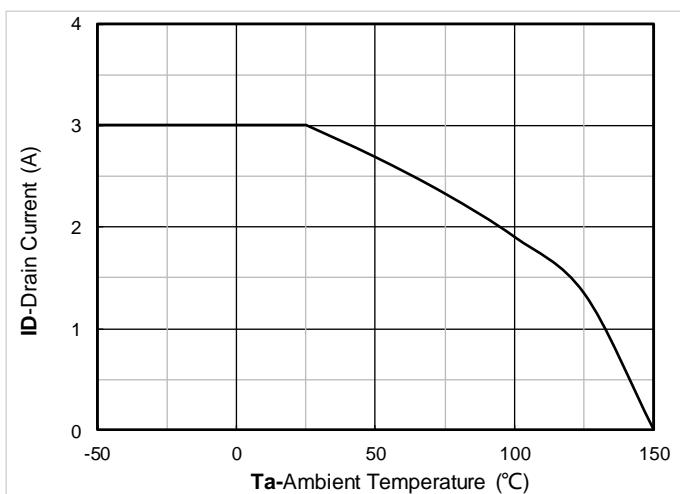


Figure 11. Current dissipation

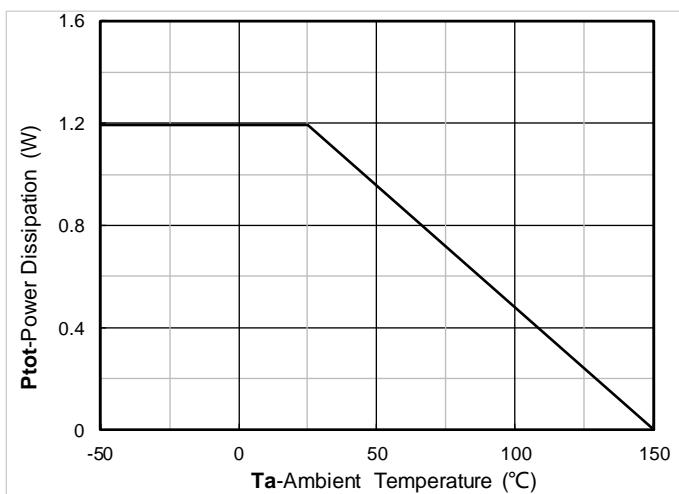


Figure 12. Power dissipation

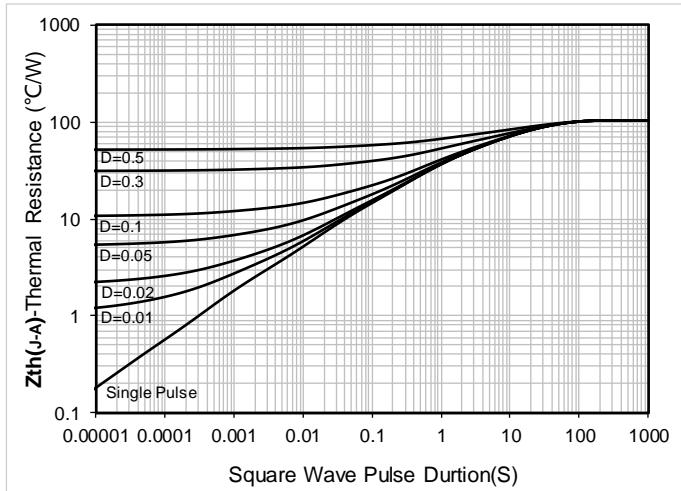


Figure 13. Maximum Transient Thermal Impedance

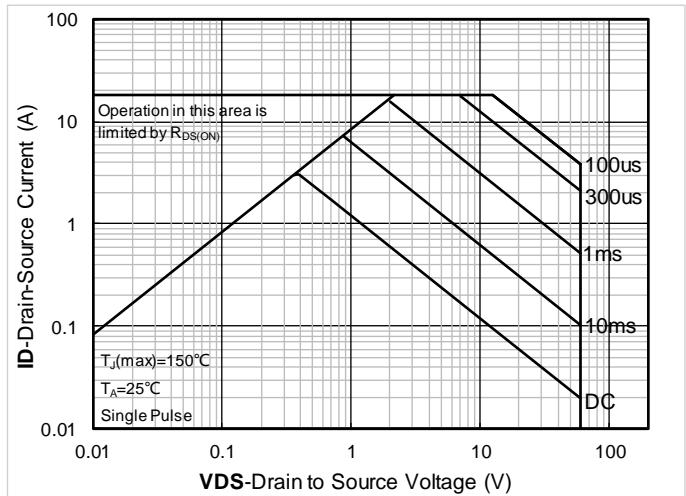


Figure 14. Safe Operation Area

## ■ Test Circuits & Waveforms

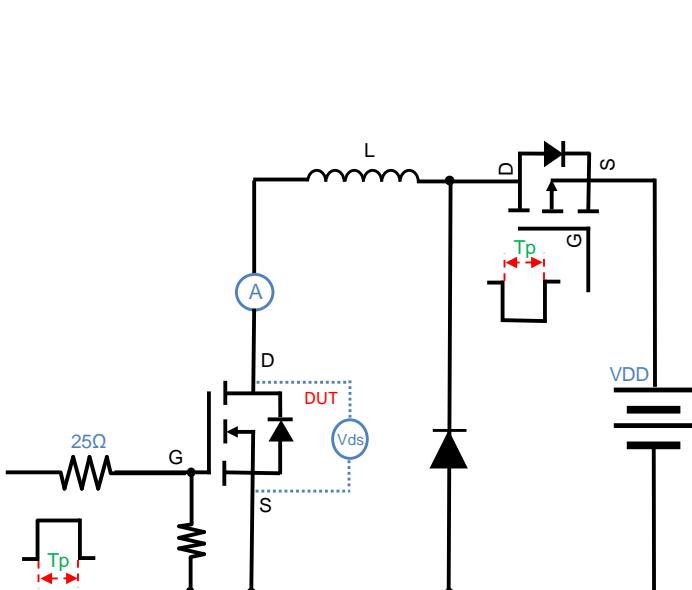
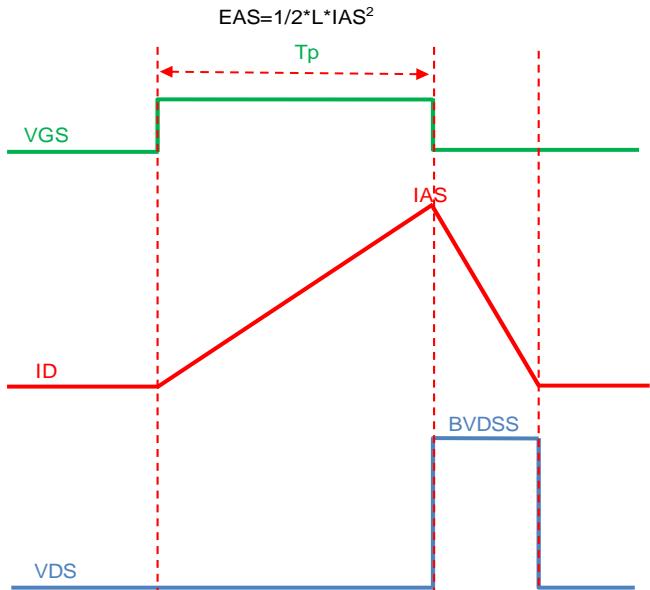


Figure A. Unclamped Inductive Switching (UIS) Test Circuit &amp; Waveform



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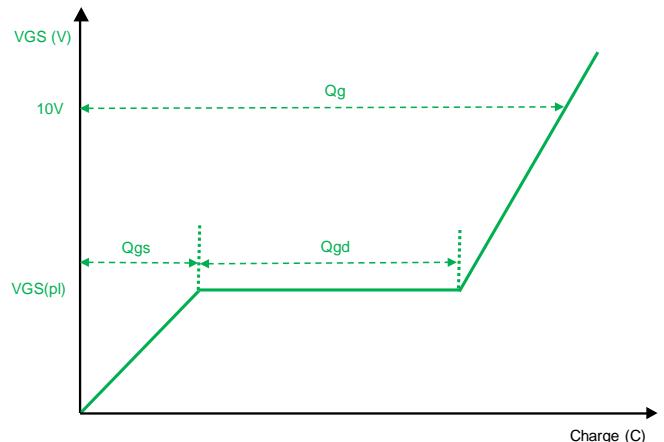
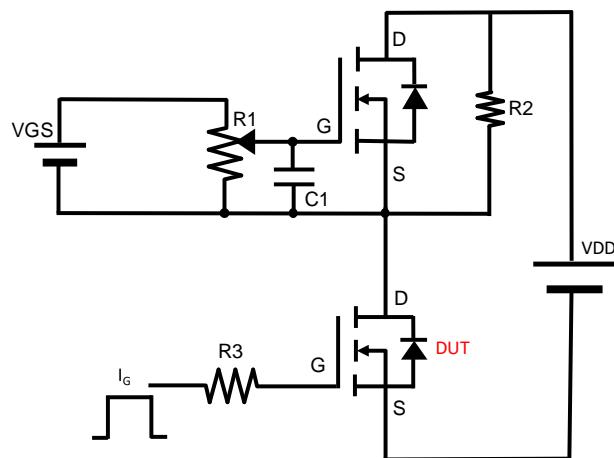


Figure B. Gate Charge Test Circuit &amp; Waveform

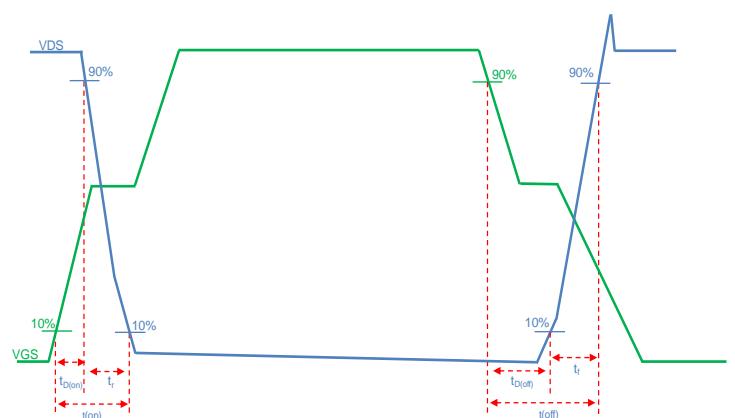
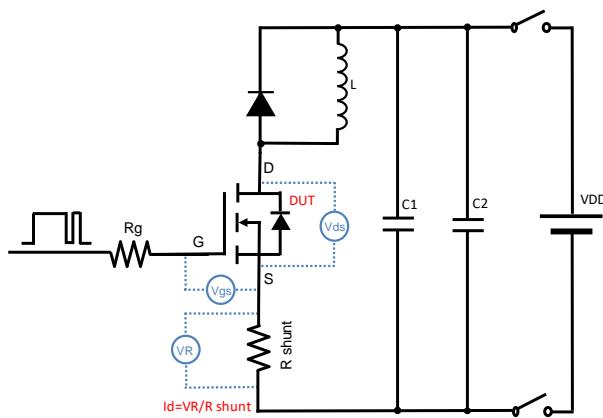


Figure C. Resistive Switching Test Circuit &amp; Waveform

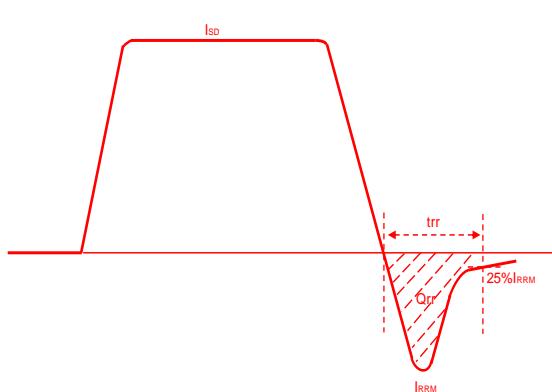
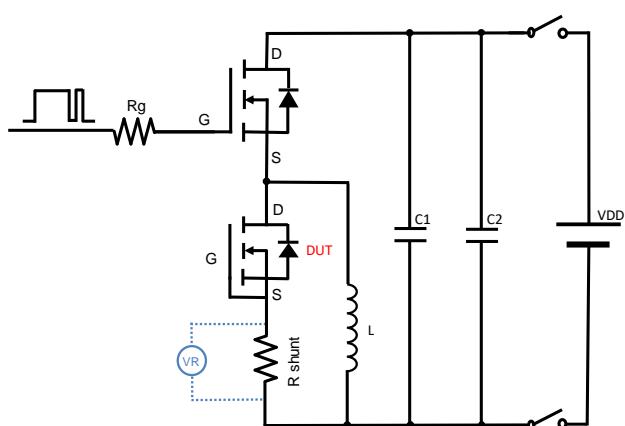
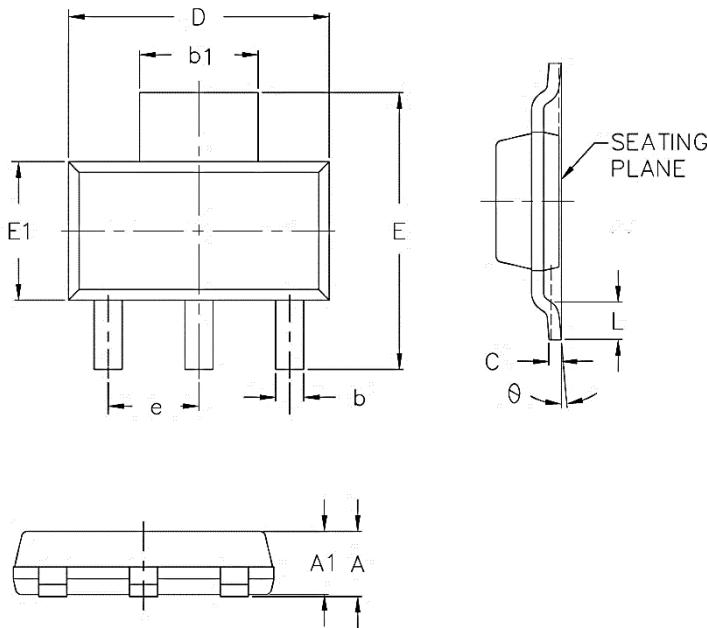


Figure D. Diode Recovery Test Circuit &amp; Waveform

**Mechanical Dimensions for SOT-223-3L****COMMON DIMENSIONS**

SYMBOL	MM	
	MIN	MAX
A	-	1.80
A1	1.45	1.75
b	0.60	0.84
b1	2.90	3.10
C	0.23	0.35
D	6.20	6.70
E	6.70	7.30
E1	3.30	3.70
e	2.30BSC	
L	0.80	-
θ	0°	10°